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TABLE OF CONTENTS

High-Throughput Time-Domain Neuromorphic Computing Using Memristors and ECRAM	1
<i>Hagar Hendy, Elaine Greenfield, Huayuan Han, Jacob O'Donnell, Ke Xu, Cory Merkel, Tejasvi Das</i>	
An Energy Efficient Crossbar MAC Array with 128 Conductance State ECRAM Devices	6
<i>Huayuan Han, Jason Inman, Stefan Maczynski, Mark Indovina, Amlan Ganguly, Tejasvi Das, Ke Xu</i>	
On the Design and Fabrication of PATH-Based In-Memory Computing Multipliers	12
<i>Jinam J. Modasiya, Venkata Nithin Kamineni, Muhammad Rashedul Haq Rashed, Maximilian Liehr, Sumit Kumar Jha, Rickard Ewetz, Nathaniel C. Cady</i>	
SARHD: A 6T-SRAM Based Side-Channel Attack Resilient Brain-Inspired Hyperdimensional Computing Architecture	20
<i>Md Rubel Sarkar, Shirazush Salekin Chowdhury, Govind Sunil Kumar, Cindy Yang Yi</i>	
A Hebbian Learning Based Spiking Neuromorphic Hardware Accelerator with ReRAM.....	26
<i>W. Hokenmaier, R. Jurasek, E. McNeil, Darin Daudelin</i>	
Watermarking Superconducting Electronic Circuits in Classical and Quantum Computers	31
<i>Ayisat Adedokun, Yerzhan Mustafa, Selçuk Köse</i>	
A 7nW, 55 μm^2 DC Process Monitor with Linear Temperature Tracking	37
<i>Ramana Ranganatham, Roberto Ramos-Brito, Tejasvi Das</i>	
Testing Strategies for Ferroelectric BTO Films and BTO-IGZO Ferroelectric FETs for Analog Memory Applications	43
<i>Nicholas Haehn, Connor Socolik, Vamshi Kiran Gogi, Siddharth Barve, Joshua Mayersky, Amber Reed, Kevin Leedy, Rashmi Jha</i>	
Effect of Growth Conditions on the Performance of Vertically Conducting $\beta\text{-Ga}_2\text{O}_3$ Diodes on 4H-SiC Substrate	49
<i>Nifat Jahan Nipa, Kai Fu, Mohammad Tahir Hassan, Dongkyu Lee, Botong Li, Iftikhar Ahmad</i>	
Investigating the Limitations of Desat Protection for WBG Semiconductors: Conjoint Effects Due to the Parasitic Inductances, Junction Temperature and Dynamic Drain-Source Resistance	54
<i>Annoy Kumar Das, Tian Qiu, Zheyu Zhang</i>	
Effect of Charge Imbalance on the Balanced Optimized Superjunction Structures in GaN.....	60
<i>Monzurul Alam</i>	
A Generative-Model-Assisted Optimizer for Restoring Transmission Performance.....	66
<i>Junting Deng, Ethan Chen, Vanessa Chen</i>	
Design for Testability of a CMOS Dynamic Bias Comparator for Through-Wafer Two-Photon Absorption Pulsed-Laser Testing.....	71
<i>Andrew Ash, Ickhyun Song, John O'Hara, John Hu</i>	
Phase Signal Classification with Reservoir Computing	77
<i>Md Rubel Sarkar, Shirazush Salekin Chowdhury, Jeffrey S. Walling, Cindy Yang Yi</i>	

Microelectronics Differential Impedance Spectrometry System: Modeling and Noise Analysis for Biomedical Sensing Applications	83
<i>Muhammad Nabeel Tahir, Umer Hassan</i>	
Thin-Film Hall Sensors for Detecting Micron-Scale Magnetic Particles Using a Computational Study.....	89
<i>Harshitha Govindaraju, Umer Hassan</i>	
ECG-Driven Automatic Personality Trait Identification	94
<i>Timothy C. Sweeney-Fanelli, Justin C. Au-Yeung, Naveenkumar G. Venkataswamy, Masudul H. Imtiaz</i>	
Securing the Interconnect in Heterogeneous 3DICs: Threats and Emerging Solutions.....	103
<i>Dipal Halder, Sandip Ray</i>	
NIST 800-22 Statistical Validation of SRAM-Based PUFs for Hardware Security	109
<i>Zain Ul Abideen</i>	
CAPRI6: A Solution for Fault Root Cause Detection.....	113
<i>Dillibabu Shanmugam, Zhenyuan Liu, Patrick Schaumont</i>	
LVS Rule File Connectivity Network: A Novel LVS Rule File Qualification for Enhanced Connectivity and Parasitic Extraction in Advanced Semiconductor Designs.....	120
<i>Jaeyoung So, Heejae Lim, Minho Jung, Yunseong Lee, Ahmed Saleh, Jimin Yeo, Jiyoung Shin, Mohamed Alimam</i>	
Design and Fabrication of a Memory Test Vehicle (MTV) for Emerging Memory Devices.....	125
<i>Rajas Mathkari, Jinam J. Modasiya, Karsten Beckmann, Natalya Tokranova, Maximilian Liehr, Nathaniel C. Cady</i>	
Emerging Non-Volatile Memories Based on Ferroelectric AlScN and Testing Approaches	131
<i>Vamshi Kiran Gogi, Siddharth Barve, Rashmi Jha</i>	
Improved Resistance Model for MOSFET Gate with High Accuracy Based on Measurement Results for Simulation Verification	136
<i>Juri Lee, Jongku Kang, Jiyoung Shin, Sungyup Jung, Daehu Lee, Daehyun Park, Jungho Park, Taeyoon Lee, Sungjae Lee</i>	
A Low-Power Wireless CTD Sonde for Long-Range Oceanographic Monitoring	140
<i>Parmida Amngostar, Soheyl Faghir Hagh, Tian Xia</i>	
A Hybrid Metrology and Inspection System for Micro-Sheet Resistance Measurements.....	146
<i>Zehao Li, Pardeep Kumar, Kwame Amponsah</i>	
A 39 GHz Circularly Polarized Meta-Atom Antenna Design.....	152
<i>Swarup Chakraborty, Tahir Bashir, Wei Li, Tian Xia</i>	
"Pseudo-Soft Defects": A Critical Examination of Their Effects on Analog Circuit Performance.....	158
<i>Kelvin Tamakloe, Godfred Bonsu, Michael Sekyere, Marampally Saikiran, Degang Chen</i>	
A Simple Monitor for Tracking Leakage Current in Capacitors for Reliability Assessment.....	164
<i>Emmanuel Nti Darko, Saeid Karimpour, Daniel Adjei, Kelvin Tamakloe, Degang Chen</i>	

Author Index